Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/613,569	CHEN, PAUL
Examiner	Art Unit
Fenn C. Mathew	3764

SEARCHED			
Class	Subclass	Date	Examiner
482	97-100		FCM
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	106-108		
	142		
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INTERFERENCE SEARCHED			
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